WHAT IS CLAIMED IS:

- 1. A method for microscopy comprising the steps of:
 - generating pulsed illuminating light that comprises wavelengths which lie in a spectral region;
 - defining a detection spectral region that lies within the spectral region;
 - influencing the light components of the illuminating light that comprise wavelengths within the detection spectral region;
 - illuminating a specimen with the illuminating light; and
 - detecting the detection light proceeding from the specimen within the detection spectral region.
- 2. The method as defined in Claim 1, wherein the influencing includes a removal of the light components of the illuminating light that comprise wavelengths within the detection spectral region.
- 3. The method as defined in Claim 1, wherein the influencing contains a modification of the polarization state of the light components of the illuminating light that comprise wavelengths within the detection spectral region.
- 4. The method as defined in Claim 3, wherein the modification of the polarization state encompasses a rotation of a linear polarization.
- 5. The method as defined in Claim 1, wherein the influencing encompasses a spectral filtration.
- 6. The method as defined in Claim 1, wherein the wavelength of the illuminating light lies outside the detection spectral region.

- 7. The method as defined in Claim 1, wherein a pulsed laser is provided for generating the pulsed illuminating light.
- 8. A microscope having a light source for generating pulsed illuminating light that comprises light from a spectral region, and having at least one detector for detecting the detection light proceeding from a specimen in a detection spectral region, wherein the detection spectral region lies within the spectral region; and the illuminating light contains no light from the detection spectral region having the same polarization properties.
- 9. The microscope as defined in Claim 8, wherein the illuminating light contains no light from the detection spectral region.
- 10. The microscope as defined in Claim 8, further comprising a spectral filter that modifies the polarization state of the light components of the illuminating light that comprise wavelengths within the detection spectral region.
- 11. The microscope as defined in Claim 8, further comprising a spectral filter that removes from the illuminating light the light components of the illuminating light that comprise wavelengths within the detection spectral region.
- 12. The microscope as defined in Claim 11, further comprising a further spectral filter that allows only light of the wavelengths of the detection spectral region to arrive at the detector.
- 13. The microscope as defined in Claim 12, wherein the further spectral filter is inverse with respect to the spectral filter.

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- 14. A confocal scanning microscope having a light source for generating pulsed illuminating light that comprises light from a spectral region, and having at least one detector for detecting the detection light proceeding from a specimen in a detection spectral region, wherein the detection spectral region lies within the spectral region; and the illuminating light contains no light from the detection spectral region having the same polarization properties.
- 15. The confocal scanning microscope as defined in Claim 14, wherein the illuminating light contains no light from the detection spectral region.
- 16. The confocal scanning microscope as defined in Claim 14, further comprising a spectral filter that modifies the polarization state of the light components of the illuminating light that comprise wavelengths within the detection spectral region.
- 17. The confocal scanning microscope as defined in Claim 14, further comprising a spectral filter that removes from the illuminating light the light components of the illuminating light that comprise wavelengths within the detection spectral region.
- 18. The confocal scanning microscope as defined in Claim 17, further comprising a further spectral filter that allows only light of the wavelengths of the detection spectral region to arrive at the detector.
- 19. The confocal scanning microscope as defined in Claim 18, wherein the further spectral filter is inverse with respect to the spectral filter.